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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

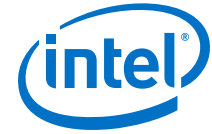
Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	2500
Number of Logic Elements/Cells	40000
Total RAM Bits	1290240
Number of I/O	360
Number of Gates	-
Voltage - Supply	1.15V ~ 1.25V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	484-BGA
Supplier Device Package	484-FBGA (23x23)
Purchase URL	https://www.e-xfl.com/product-detail/intel/10m40daf484i7g



Symbol	Parameter	Condition	Min	Typ	Max	Unit
$V_{CCA}^{(1)}$	Supply voltage for PLL regulator and ADC block (analog)	1.35 V	1.2825	1.35	1.4175	V
		1.2 V	1.14	1.2	1.26	V
		—	2.85/3.135	3.0/3.3	3.15/3.465	V

Dual Supply Devices Power Supplies Recommended Operating Conditions

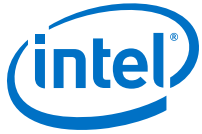
Table 7. Power Supplies Recommended Operating Conditions for Intel MAX 10 Dual Supply Devices

Symbol	Parameter	Condition	Min	Typ	Max	Unit
V_{CC}	Supply voltage for core and periphery	—	1.15	1.2	1.25	V
$V_{CCIO}^{(3)}$	Supply voltage for input and output buffers	3.3 V	3.135	3.3	3.465	V
		3.0 V	2.85	3	3.15	V
		2.5 V	2.375	2.5	2.625	V
		1.8 V	1.71	1.8	1.89	V
		1.5 V	1.425	1.5	1.575	V
		1.35 V	1.2825	1.35	1.4175	V
		1.2 V	1.14	1.2	1.26	V
$V_{CCA}^{(4)}$	Supply voltage for PLL regulator (analog)	—	2.375	2.5	2.625	V
$V_{CCD_PLL}^{(5)}$	Supply voltage for PLL regulator (digital)	—	1.15	1.2	1.25	V
V_{CCA_ADC}	Supply voltage for ADC analog block	—	2.375	2.5	2.625	V
V_{CCINT}	Supply voltage for ADC digital block	—	1.15	1.2	1.25	V

⁽³⁾ V_{CCIO} for all I/O banks must be powered up during user mode because V_{CCIO} I/O banks are used for the ADC and I/O functionalities.

⁽⁴⁾ All V_{CCA} pins must be powered to 2.5 V (even when PLLs are not used), and must be powered up and powered down at the same time.

⁽⁵⁾ V_{CCD_PLL} must always be connected to V_{CC} through a decoupling capacitor and ferrite bead.



Recommended Operating Conditions

Table 8. Recommended Operating Conditions for Intel MAX 10 Devices

Symbol	Parameter	Condition	Min	Max	Unit
V _I	DC input voltage	—	−0.5	3.6	V
V _O	Output voltage for I/O pins	—	0	V _{CCIO}	V
T _J	Operating junction temperature	Commercial	0	85	°C
		Industrial	−40 ⁽⁶⁾	100	°C
		Automotive	−40 ⁽⁶⁾	125	°C
t _{RAMP}	Power supply ramp time	—	(7)	10	ms
I _{Diode}	Magnitude of DC current across PCI* clamp diode when enabled	—	—	10	mA

Programming/Erase Specifications

Table 9. Programming/Erase Specifications for Intel MAX 10 Devices

This table shows the programming cycles and data retention duration of the user flash memory (UFM) and configuration flash memory (CFM) blocks.

For more information about data retention duration with 10,000 programming cycles for automotive temperature devices, contact your Intel quality representative.

Erase and reprogram cycles (E/P) ⁽⁸⁾ (Cycles/page)	Temperature (°C)	Data retention duration (Years)
10,000	85	20
10,000	100	10

⁽⁶⁾ −40°C is only applicable to Start of Test, when the device is powered-on. The device does not stay at the minimum junction temperature for a long time.

⁽⁷⁾ There is no absolute minimum value for the ramp time requirement. Intel characterized the minimum ramp time at 200 µs.

⁽⁸⁾ The number of E/P cycles applies to the smallest possible flash block that can be erased or programmed in each Intel MAX 10 device. Each Intel MAX 10 device has multiple flash pages per device.

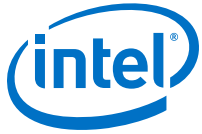


Table 11. ADC_VREF Pin Leakage Current for Intel MAX 10 Devices

Symbol	Parameter	Condition	Min	Max	Unit
$I_{\text{adc_vref}}$	ADC_VREF pin leakage current	Single supply mode	—	10	μA
		Dual supply mode	—	20	μA

Bus Hold Parameters

Bus hold retains the last valid logic state after the source driving it either enters the high impedance state or is removed. Each I/O pin has an option to enable bus hold in user mode. Bus hold is always disabled in configuration mode.

Table 12. Bus Hold Parameters for Intel MAX 10 Devices

Parameter	Condition	V _{CCIO} (V)												Unit
		1.2		1.5		1.8		2.5		3.0		3.3		
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Bus-hold low, sustaining current	V _{IN} > V _{IL} (maximum)	8	—	12	—	30	—	50	—	70	—	70	—	μA
Bus-hold high, sustaining current	V _{IN} < V _{IH} (minimum)	−8	—	−12	—	−30	—	−50	—	−70	—	−70	—	μA
Bus-hold low, overdrive current	0 V < V _{IN} < V _{CCIO}	—	125	—	175	—	200	—	300	—	500	—	500	μA
Bus-hold high, overdrive current	0 V < V _{IN} < V _{CCIO}	—	−125	—	−175	—	−200	—	−300	—	−500	—	−500	μA
Bus-hold trip point	—	0.3	0.9	0.375	1.125	0.68	1.07	0.7	1.7	0.8	2	0.8	2	V

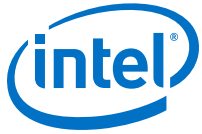


Table 15. OCT Variation after Calibration at Device Power-Up for Intel MAX 10 Devices

This table lists the change percentage of the OCT resistance with voltage and temperature.

Description	Nominal Voltage	dR/dT (%/°C)	dR/dV (%/mV)
OCT variation after calibration at device power-up	3.00	0.25	-0.027
	2.50	0.245	-0.04
	1.80	0.242	-0.079
	1.50	0.235	-0.125
	1.35	0.229	-0.16
	1.20	0.197	-0.208

Figure 1. Equation for OCT Resistance after Calibration at Device Power-Up

$$\Delta R_V = (V_2 - V_1) \times 1000 \times dR/dV$$

$$\Delta R_T = (T_2 - T_1) \times dR/dT$$

$$\text{For } \Delta R_X < 0; MF_X = 1/(|\Delta R_X|/100 + 1)$$

$$\text{For } \Delta R_X > 0; MF_X = \Delta R_X/100 + 1$$

$$MF = MF_V \times MF_T$$

$$R_{final} = R_{initial} \times MF$$

The definitions for equation are as follows:

- T_1 is the initial temperature.
- T_2 is the final temperature.
- MF is multiplication factor.
- $R_{initial}$ is initial resistance.
- R_{final} is final resistance.



Table 19. Hysteresis Specifications for Schmitt Trigger Input for Intel MAX 10 Devices

Symbol	Parameter	Condition	Minimum	Unit
V _{HYS}	Hysteresis for Schmitt trigger input	V _{CCIO} = 3.3 V	180	mV
		V _{CCIO} = 2.5 V	150	mV
		V _{CCIO} = 1.8 V	120	mV
		V _{CCIO} = 1.5 V	110	mV



I/O Standard	V _{IL(DC)} (V)		V _{IH(DC)} (V)		V _{IL(AC)} (V)		V _{IH(AC)} (V)		V _{OL} (V)	V _{OH} (V)	I _{OL} (mA)	I _{OH} (mA)
	Min	Max	Min	Max	Min	Max	Min	Max	Max	Min		
HSTL-12 Class I	-0.15	V _{REF} - 0.08	V _{REF} + 0.08	V _{CCIO} + 0.15	-0.24	V _{REF} - 0.15	V _{REF} + 0.15	V _{CCIO} + 0.24	0.25 × V _{CCIO}	0.75 × V _{CCIO}	8	-8
HSTL-12 Class II	-0.15	V _{REF} - 0.08	V _{REF} + 0.08	V _{CCIO} + 0.15	-0.24	V _{REF} - 0.15	V _{REF} + 0.15	V _{CCIO} + 0.24	0.25 × V _{CCIO}	0.75 × V _{CCIO}	14	-14
HSUL-12	—	V _{REF} - 0.13	V _{REF} + 0.13	—	—	V _{REF} - 0.22	V _{REF} + 0.22	—	0.1 × V _{CCIO}	0.9 × V _{CCIO}	—	—

Differential SSTL I/O Standards Specifications

Differential SSTL requires a V_{REF} input.

Table 23. Differential SSTL I/O Standards Specifications for Intel MAX 10 Devices

I/O Standard	V _{CCIO} (V)			V _{Swing(DC)} (V)		V _{X(AC)} (V)			V _{Swing(AC)} (V)	
	Min	Typ	Max	Min	Max ⁽¹⁷⁾	Min	Typ	Max	Min	Max
SSTL-2 Class I, II	2.375	2.5	2.625	0.36	V _{CCIO}	V _{CCIO} /2 - 0.2	—	V _{CCIO} /2 + 0.2	0.7	V _{CCIO}
SSTL-18 Class I, II	1.7	1.8	1.9	0.25	V _{CCIO}	V _{CCIO} /2 - 0.175	—	V _{CCIO} /2 + 0.175	0.5	V _{CCIO}
SSTL-15 Class I, II	1.425	1.5	1.575	0.2	—	V _{CCIO} /2 - 0.15	—	V _{CCIO} /2 + 0.15	2(V _{IH(AC)} - V _{REF})	2(V _{IL(AC)} - V _{REF})
SSTL-135	1.283	1.35	1.45	0.18	—	V _{REF} - 0.135	0.5 × V _{CCIO}	V _{REF} + 0.135	2(V _{IH(AC)} - V _{REF})	2(V _{IL(AC)} - V _{REF})

Differential HSTL and HSUL I/O Standards Specifications

Differential HSTL requires a V_{REF} input.

⁽¹⁷⁾ The maximum value for V_{SWING(DC)} is not defined. However, each single-ended signal needs to be within the respective single-ended limits (V_{IH(DC)} and V_{IL(DC)}).

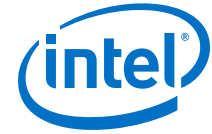


Table 24. Differential HSTL and HSUL I/O Standards Specifications for Intel MAX 10 Devices

I/O Standard	V _{CCIO} (V)			V _{DIF(DC)} (V)		V _{X(AC)} (V)			V _{CM(DC)} (V)			V _{DIF(AC)} (V)
	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Typ	Max	Min
HSTL-18 Class I, II	1.71	1.8	1.89	0.2	—	0.85	—	0.95	0.85	—	0.95	0.4
HSTL-15 Class I, II	1.425	1.5	1.575	0.2	—	0.71	—	0.79	0.71	—	0.79	0.4
HSTL-12 Class I, II	1.14	1.2	1.26	0.16	V _{CCIO}	0.48 × V _{CCIO}	0.5 × V _{CCIO}	0.52 × V _{CCIO}	0.48 × V _{CCIO}	0.5 × V _{CCIO}	0.52 × V _{CCIO}	0.3
HSUL-12	1.14	1.2	1.3	0.26	—	0.5 × V _{CCIO} – 0.12	0.5 × V _{CCIO}	0.5 × V _{CCIO} + 0.12	0.4 × V _{CCIO}	0.5 × V _{CCIO}	0.6 × V _{CCIO}	0.44

Differential I/O Standards Specifications

Table 25. Differential I/O Standards Specifications for Intel MAX 10 Devices

I/O Standard	V _{CCIO} (V)			V _{ID} (mV)		V _{ICM} (V) ⁽¹⁸⁾			V _{OD} (mV) ⁽¹⁹⁾⁽²⁰⁾			V _{OS} (V) ⁽¹⁹⁾		
	Min	Typ	Max	Min	Max	Min	Condition	Max	Min	Typ	Max	Min	Typ	Max
LVPECL ⁽²¹⁾	2.375	2.5	2.625	100	—	0.05	D _{MAX} ≤ 500 Mbps	1.8	—	—	—	—	—	—
						0.55	500 Mbps ≤ D _{MAX} ≤ 700 Mbps	1.8						
						1.05	D _{MAX} > 700 Mbps	1.55						
LVDS	2.375	2.5	2.625	100	—	0.05	D _{MAX} ≤ 500 Mbps	1.8	247	—	600	1.125	1.25	1.375
						0.55	500 Mbps ≤ D _{MAX} ≤ 700 Mbps	1.8						

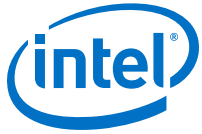
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⁽¹⁸⁾ V_{IN} range: 0 V ≤ V_{IN} ≤ 1.85 V.

⁽¹⁹⁾ R_L range: 90 ≤ R_L ≤ 110 Ω.

⁽²⁰⁾ Low V_{OD} setting is only supported for RSDS standard.

⁽²¹⁾ LVPECL input standard is only supported at clock input. Output standard is not supported.

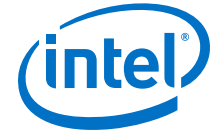


I/O Standard	V _{CCIO} (V)			V _{ID} (mV)		V _{ICM} (V) ⁽¹⁸⁾			V _{OD} (mV) ⁽¹⁹⁾⁽²⁰⁾			V _{OS} (V) ⁽¹⁹⁾		
	Min	Typ	Max	Min	Max	Min	Condition	Max	Min	Typ	Max	Min	Typ	Max
						1.05	D _{MAX} > 700 Mbps	1.55						
BLVDS ⁽²²⁾	2.375	2.5	2.625	100	—	—	—	—	—	—	—	—	—	—
mini-LVDS ⁽²³⁾	2.375	2.5	2.625	—	—	—	—	—	300	—	600	1	1.2	1.4
RSDS ⁽²³⁾	2.375	2.5	2.625	—	—	—	—	—	100	200	600	0.5	1.2	1.5
PPDS (Row I/Os) ⁽²³⁾	2.375	2.5	2.625	—	—	—	—	—	100	200	600	0.5	1.2	1.4
TMDS ⁽²⁴⁾	2.375	2.5	2.625	100	—	0.05	D _{MAX} ≤ 500 Mbps	1.8	—	—	—	—	—	—
						0.55	500 Mbps ≤ D _{MAX} ≤ 700 Mbps	1.8						
						1.05	D _{MAX} > 700 Mbps	1.55						
Sub-LVDS ⁽²⁵⁾	1.71	1.8	1.89	100	—	0.55	—	1.25	⁽²⁶⁾			0.8	0.9	1
SLVS	2.375	2.5	2.625	100	—	0.05	—	1.1	⁽²⁶⁾			⁽²⁷⁾		
continued...														

⁽¹⁸⁾ V_{IN} range: 0 V ≤ V_{IN} ≤ 1.85 V.

⁽¹⁹⁾ R_L range: 90 ≤ R_L ≤ 110 Ω.

⁽²⁰⁾ Low V_{OD} setting is only supported for RSBS standard.



I/O Standard	V _{CCIO} (V)			V _{ID} (mV)		V _{ICM} (V) ⁽¹⁸⁾			V _{OD} (mV) ⁽¹⁹⁾⁽²⁰⁾			V _{OS} (V) ⁽¹⁹⁾		
	Min	Typ	Max	Min	Max	Min	Condition	Max	Min	Typ	Max	Min	Typ	Max
HiSpi	2.375	2.5	2.625	100	—	0.05	D _{MAX} ≤ 500 Mbps	1.8	—	—	—	—	—	—
						0.55	500 Mbps ≤ D _{MAX} ≤ 700 Mbps	1.8						
						1.05	D _{MAX} > 700 Mbps	1.55						

Related Information

[Intel MAX 10 LVDS SERDES I/O Standards Support, Intel MAX 10 High-Speed LVDS I/O User Guide](#)
Provides the list of I/O standards supported in single supply and dual supply devices.

Switching Characteristics

This section provides the performance characteristics of Intel MAX 10 core and periphery blocks.

⁽¹⁸⁾ V_{IN} range: 0 V ≤ V_{IN} ≤ 1.85 V.

⁽¹⁹⁾ R_L range: 90 Ω ≤ R_L ≤ 110 Ω.

⁽²⁰⁾ Low V_{OD} setting is only supported for RSDS standard.

⁽²²⁾ No fixed V_{IN}, V_{OD}, and V_{OS} specifications for Bus LVDS (BLVDS). They are dependent on the system topology.

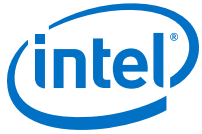
⁽²³⁾ Mini-LVDS, RSDS, and Point-to-Point Differential Signaling (PPDS) standards are only supported at the output pins for Intel MAX 10 devices.

⁽²⁴⁾ Supported with requirement of an external level shift

⁽²⁵⁾ Sub-LVDS input buffer is using 2.5 V differential buffer.

⁽²⁶⁾ Differential output depends on the values of the external termination resistors.

⁽²⁷⁾ Differential output offset voltage depends on the values of the external termination resistors.



Symbol	Parameter	Condition	Min	Typ	Max	Unit
t_{PLL_PSERR}	Accuracy of PLL phase shift	—	—	—	±50	ps
t_{ARESET}	Minimum pulse width on areset signal.	—	10	—	—	ns
$t_{CONFIGPLL}$	Time required to reconfigure scan chains for PLLs	—	—	3.5 ⁽³²⁾	—	SCANCLK cycles
$f_{SCANCLK}$	scanclk frequency	—	—	—	100	MHz

Table 28. PLL Specifications for Intel MAX 10 Single Supply Devices

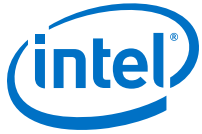
For V36 package, the PLL specification is based on single supply devices.

Symbol	Parameter	Condition	Max	Unit
$t_{OUTJITTER_PERIOD_DEDCLK}$ ⁽³¹⁾	Dedicated clock output period jitter	$F_{OUT} \geq 100$ MHz	660	ps
		$F_{OUT} < 100$ MHz	66	mUI
$t_{OUTJITTER_CCJ_DEDCLK}$ ⁽³¹⁾	Dedicated clock output cycle-to-cycle jitter	$F_{OUT} \geq 100$ MHz	660	ps
		$F_{OUT} < 100$ MHz	66	mUI

Table 29. PLL Specifications for Intel MAX 10 Dual Supply Devices

Symbol	Parameter	Condition	Max	Unit
$t_{OUTJITTER_PERIOD_DEDCLK}$ ⁽³¹⁾	Dedicated clock output period jitter	$F_{OUT} \geq 100$ MHz	300	ps
		$F_{OUT} < 100$ MHz	30	mUI
$t_{OUTJITTER_CCJ_DEDCLK}$ ⁽³¹⁾	Dedicated clock output cycle-to-cycle jitter	$F_{OUT} \geq 100$ MHz	300	ps
		$F_{OUT} < 100$ MHz	30	mUI

⁽³²⁾ With 100 MHz scanclk frequency.



Parameter		Symbol	Condition	Min	Typ	Max	Unit
	Integral non linearity	INL	—	–2	—	2	LSB
AC Accuracy	Total harmonic distortion	THD	$F_{IN} = 50 \text{ kHz}$, $F_S = 1 \text{ MHz}$, PLL	–65 ⁽³⁷⁾	—	—	dB
	Signal-to-noise ratio	SNR	$F_{IN} = 50 \text{ kHz}$, $F_S = 1 \text{ MHz}$, PLL	54 ⁽³⁸⁾	—	—	dB
	Signal-to-noise and distortion	SINAD	$F_{IN} = 50 \text{ kHz}$, $F_S = 1 \text{ MHz}$, PLL	53 ⁽³⁹⁾	—	—	dB
On-Chip Temperature Sensor	Temperature sampling rate	T_S	—	—	—	50	kSPS
	Absolute accuracy	—	–40 to 125°C, with 64 samples averaging ⁽⁴⁰⁾	—	—	±10	°C
Conversion Rate ⁽⁴¹⁾	Conversion time	—	Single measurement	—	—	1	Cycle
			Continuous measurement	—	—	1	Cycle
			Temperature measurement	—	—	1	Cycle

Related Information

[SPICE Models for Intel FPGAs](#)

⁽³⁷⁾ THD with prescaler enabled is 6dB less than the specification.

⁽³⁸⁾ SNR with prescaler enabled is 6dB less than the specification.

⁽³⁹⁾ SINAD with prescaler enabled is 6dB less than the specification.

⁽⁴⁰⁾ For the Intel Quartus Prime software version 15.0 and later, Modular ADC Core Intel FPGA IP and Modular Dual ADC Core Intel FPGA IP cores handle the 64 samples averaging. For the Intel Quartus Prime software versions prior to 14.1, you need to implement your own averaging calculation.

⁽⁴¹⁾ For more detailed description, refer to the Timing section in the *Intel MAX 10 Analog-to-Digital Converter User Guide*.



Parameter		Symbol	Condition	Min	Typ	Max	Unit
Conversion Rate ⁽⁵²⁾	Conversion time	—	Single measurement	—	—	1	Cycle
			Continuous measurement	—	—	1	Cycle
			Temperature measurement	—	—	1	Cycle

Related Information

[SPICE Models for Intel FPGAs](#)

Periphery Performance Specifications

This section describes the periphery performance, high-speed I/O, and external memory interface.

Actual achievable frequency depends on design and system specific factors. Ensure proper timing closure in your design and perform HSPICE/IBIS simulations based on your specific design and system setup to determine the maximum achievable frequency in your system.

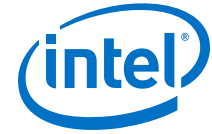
High-Speed I/O Specifications

For more information about the high-speed and low-speed I/O performance pins, refer to the respective device pin-out files.

Related Information

[Documentation: Pin-Out Files for Intel FPGAs](#)

⁽⁵²⁾ For more detailed description, refer to the Timing section in the *Intel MAX 10 Analog-to-Digital Converter User Guide*.



Symbol	Parameter	Mode	-I6, -A6, -C7, -I7			-A7			-C8			Unit
			Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
		×4	40	—	300	40	—	300	40	—	300	Mbps
		×2	20	—	300	20	—	300	20	—	300	Mbps
		×1	10	—	300	10	—	300	10	—	300	Mbps
t _{DUTY}	Duty cycle on transmitter output clock	—	45	—	55	45	—	55	45	—	55	%
TCCS ⁽⁵³⁾	Transmitter channel-to-channel skew	—	—	—	300	—	—	300	—	—	300	ps
t _{x jitter} ⁽⁵⁴⁾	Output jitter (high-speed I/O performance pin)	—	—	—	425	—	—	425	—	—	425	ps
	Output jitter (low-speed I/O performance pin)	—	—	—	470	—	—	470	—	—	470	ps
t _{RISE}	Rise time	20 – 80%, C _{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	ps
t _{FALL}	Fall time	20 – 80%, C _{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	ps
t _{LOCK}	Time required for the PLL to lock, after CONF_DONE signal goes high, indicating the completion of device configuration	—	—	—	1	—	—	1	—	—	1	ms

⁽⁵³⁾ TCCS specifications apply to I/O banks from the same side only.

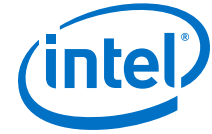
⁽⁵⁴⁾ TX jitter is the jitter induced from core noise and I/O switching noise.



Symbol	Parameter	Mode	-I6, -A6, -C7, -I7			-A7			-C8			Unit
			Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
		×4	40	—	170	40	—	170	40	—	170	Mbps
		×2	20	—	170	20	—	170	20	—	170	Mbps
		×1	10	—	170	10	—	170	10	—	170	Mbps
t _{DUTY}	Duty cycle on transmitter output clock	—	45	—	55	45	—	55	45	—	55	%
TCCS ⁽⁵⁹⁾	Transmitter channel-to-channel skew	—	—	—	300	—	—	300	—	—	300	ps
t _{x jitter} ⁽⁶⁰⁾	Output jitter (high-speed I/O performance pin)	—	—	—	425	—	—	425	—	—	425	ps
	Output jitter (low-speed I/O performance pin)	—	—	—	470	—	—	470	—	—	470	ps
t _{RISE}	Rise time	20 – 80%, C _{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	ps
t _{FALL}	Fall time	20 – 80%, C _{LOAD} = 5 pF	—	500	—	—	500	—	—	500	—	ps
t _{LOCK}	Time required for the PLL to lock, after CONF_DONE signal goes high, indicating the completion of device configuration	—	—	—	1	—	—	1	—	—	1	ms

⁽⁵⁹⁾ TCCS specifications apply to I/O banks from the same side only.

⁽⁶⁰⁾ TX jitter is the jitter induced from core noise and I/O switching noise.



LVDS, TMDs, HiSpi, SLVS, and Sub-LVDS Receiver Timing Specifications

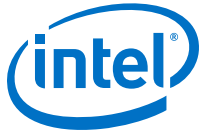
Single Supply Devices LVDS Receiver Timing Specifications

Table 45. LVDS Receiver Timing Specifications for Intel MAX 10 Single Supply Devices

LVDS receivers are supported at all banks.

Symbol	Parameter	Mode	-C7, -I7		-A7		-C8		Unit
			Min	Max	Min	Max	Min	Max	
f _{HCLK}	Input clock frequency (high-speed I/O performance pin)	×10	5	145	5	100	5	100	MHz
		×8	5	145	5	100	5	100	MHz
		×7	5	145	5	100	5	100	MHz
		×4	5	145	5	100	5	100	MHz
		×2	5	145	5	100	5	100	MHz
		×1	5	290	5	200	5	200	MHz
HSIODR	Data rate (high-speed I/O performance pin)	×10	100	290	100	200	100	200	Mbps
		×8	80	290	80	200	80	200	Mbps
		×7	70	290	70	200	70	200	Mbps
		×4	40	290	40	200	40	200	Mbps
		×2	20	290	20	200	20	200	Mbps
		×1	10	290	10	200	10	200	Mbps
f _{HCLK}	Input clock frequency (low-speed I/O performance pin)	×10	5	100	5	100	5	100	MHz
		×8	5	100	5	100	5	100	MHz
		×7	5	100	5	100	5	100	MHz
		×4	5	100	5	100	5	100	MHz
		×2	5	100	5	100	5	100	MHz
		×1	5	200	5	200	5	200	MHz
HSIODR	Data rate (low-speed I/O performance pin)	×10	100	200	100	200	100	200	Mbps

continued...



Symbol	Parameter	Mode	-I6, -A6, -C7, -I7		-A7		-C8		Unit
			Min	Max	Min	Max	Min	Max	
	Sampling window (low-speed I/O performance pin)	—	—	910	—	910	—	910	ps
$t_{x \text{ Jitter}}^{(72)}$	Input jitter	—	—	500	—	500	—	500	ps
t_{LOCK}	Time required for the PLL to lock, after CONF_DONE signal goes high, indicating the completion of device configuration	—	—	1	—	1	—	1	ms

Memory Standards Supported by the Soft Memory Controller

Table 47. Memory Standards Supported by the Soft Memory Controller for Intel MAX 10 Devices

Contact your local sales representatives for access to the -I6 or -A6 speed grade devices in the Intel Quartus Prime software.

External Memory Interface Standard	Rate Support	Speed Grade	Voltage (V)	Max Frequency (MHz)
DDR3 SDRAM	Half	-I6	1.5	303
DDR3L SDRAM	Half	-I6	1.35	303
DDR2 SDRAM	Half	-I6	1.8	200
		-I7 and -C7		167
LPDDR2 ⁽⁷³⁾	Half	-I6	1.2	200 ⁽⁷⁴⁾

Related Information

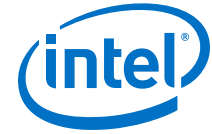
External Memory Interface Spec Estimator

Provides the specific details of the memory standards supported.

⁽⁷²⁾ TX jitter is the jitter induced from core noise and I/O switching noise.

⁽⁷³⁾ Intel MAX 10 devices support only single-die LPDDR2.

⁽⁷⁴⁾ To achieve the specified performance, constrain the memory device I/O and core power supply variation to within $\pm 3\%$. By default, the frequency is 167 MHz.



Memory Output Clock Jitter Specifications

Intel MAX 10 devices support external memory interfaces up to 303 MHz. The external memory interfaces for Intel MAX 10 devices calibrate automatically.

The memory output clock jitter measurements are for 200 consecutive clock cycles.

The clock jitter specification applies to memory output clock pins generated using DDIO circuits clocked by a PLL output routed on a PHY clock network.

DDR3 and LPDDR2 SDRAM memory interfaces are only supported on the fast speed grade device.

Table 48. Memory Output Clock Jitter Specifications for Intel MAX 10 Devices

Parameter	Symbol	–6 Speed Grade		–7 Speed Grade		Unit
		Min	Max	Min	Max	
Clock period jitter	$t_{JIT(per)}$	–127	127	–215	215	ps
Cycle-to-cycle period jitter	$t_{JIT(cc)}$	—	242	—	360	ps

Related Information

[Literature: External Memory Interfaces](#)

Provides more information about external memory system performance specifications, board design guidelines, timing analysis, simulation, and debugging information.

Configuration Specifications

This section provides configuration specifications and timing for Intel MAX 10 devices.



Table 54. Internal Configuration Time for Intel MAX 10 Devices (Compressed .rbf)

Compression ratio depends on design complexity. The minimum value is based on the best case (25% of original .rbf sizes) and the maximum value is based on the typical case (70% of original .rbf sizes).

Device	Internal Configuration Time (ms)			
	Unencrypted/Encrypted			
	Without Memory Initialization		With Memory Initialization	
	Min	Max	Min	Max
10M02	0.3	5.2	—	—
10M04	0.6	10.7	1.0	13.9
10M08	0.6	10.7	1.0	13.9
10M16	1.1	17.9	1.4	22.3
10M25	1.1	26.9	1.4	32.2
10M40	2.6	66.1	3.2	82.2
10M50	2.6	66.1	3.2	82.2

Internal Configuration Timing Parameter

Table 55. Internal Configuration Timing Parameter for Intel MAX 10 Devices

Symbol	Parameter	Device	Minimum	Maximum	Unit
t_{CD2UM}	CONF_DONE high to user mode	10M02, 10M04, 10M08, 10M16, 10M25	182.8	385.5	μ s
		10M40, 10M50	275.3	605.7	μ s

I/O Timing

The data is typically used prior to designing the FPGA to get an estimate of the timing budget as part of the link timing analysis.

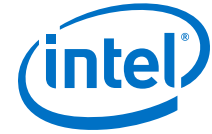
The Intel Quartus Prime Timing Analyzer provides a more accurate and precise I/O timing data based on the specific device and design after you complete place-and-route.



Term	Definition
V _{OCM}	Output common mode voltage: The common mode of the differential signal at the transmitter.
V _{OD}	Output differential voltage swing: The difference in voltage between the positive and complementary conductors of a differential transmission line at the transmitter. $V_{OD} = V_{OH} - V_{OL}$.
V _{OH}	Voltage output high: The maximum positive voltage from an output which the device considers is accepted as the minimum positive high level.
V _{OL}	Voltage output low: The maximum positive voltage from an output which the device considers is accepted as the maximum positive low level.
V _{OS}	Output offset voltage: $V_{OS} = (V_{OH} + V_{OL}) / 2$.
V _{OX (AC)}	AC differential Output cross point voltage: The voltage at which the differential output signals must cross.
V _{REF}	Reference voltage for SSTL, HSTL, and HSUL I/O Standards.
V _{REF(AC)}	AC input reference voltage for SSTL, HSTL, and HSUL I/O Standards. $V_{REF(AC)} = V_{REF(DC)} + \text{noise}$. The peak-to-peak AC noise on V _{REF} should not exceed 2% of V _{REF(DC)} .
V _{REF(DC)}	DC input reference voltage for SSTL, HSTL, and HSUL I/O Standards.
V _{SWING (AC)}	AC differential input voltage: AC Input differential voltage required for switching.
V _{SWING (DC)}	DC differential input voltage: DC Input differential voltage required for switching.
V _{TT}	Termination voltage for SSTL, HSTL, and HSUL I/O Standards.
V _{X (AC)}	AC differential Input cross point voltage: The voltage at which the differential input signals must cross.

Document Revision History for the Intel MAX 10 FPGA Device Datasheet

Document Version	Changes
2018.06.29	- Removed links on instant-on feature. - Added JTAG timing specifications term in <i>Glossary</i>. - Renamed the following IP cores as per Intel rebranding: - Renamed Altera Modular ADC IP core to Modular ADC core Intel FPGA IP core. - Renamed Altera Modular Dual ADC IP core to Modular Dual ADC core Intel FPGA IP core.



Date	Version	Changes
December 2017	2017.12.15	- Removed the units for "Input resistance" and "Input capacitance" parameters in the following tables: - ADC Performance Specifications for Intel MAX 10 Single Supply Devices - ADC Performance Specifications for Intel MAX 10 Dual Supply Devices - Removed the specification with memory initialization for 10M02 device in the <i>Uncompressed .rbf Sizes for Intel MAX 10 Devices</i> table.
June 2017	2017.06.16	- Added notes for T_J for Industrial and Automotive devices in Recommended Operating Conditions for Intel MAX 10 Devices table. - Updated the parameter in Internal Weak Pull-Up Resistor for Intel MAX 10 Devices table. - Changed "Performance" to "Frequency" in UFM Performance Specifications for Intel MAX 10 Devices table. - Removed PowerPlay text from tool name.
February 2017	2017.02.21	Rebranded as Intel.
October 2016	2016.10.31	- Updated the note to the Intel MAX 10 Device Grades and Speed Grades Supported table. - Updated the Memory Standards Supported by the Soft Memory Controller for Intel MAX 10 Devices table.
May 2016	2016.05.02	- Updated t_{RAMP} specifications in Recommended Operating Conditions for Intel MAX 10 Devices table. - Removed standard POR and fast POR specifications. - Updated maximum value from 3 ms to 10 ms and added a not for the minimum value. - Added Supply Current and Power Consumption section. - Added the following tables: - Memory Standards Supported by the Soft Memory Controller for Intel MAX 10 Devices - Internal Configuration Timing Parameter for Intel MAX 10 Devices - Removed POR Delay Specifications for Intel MAX 10 Devices table. - Updated the description in the Internal Configuration Time section. - Updated the following tables: - Internal Configuration Time for Intel MAX 10 Devices (Uncompressed .rbf) - Internal Configuration Time for Intel MAX 10 Devices (Compressed .rbf)
continued...		